



Attorney's Docket No.: 09712-330001 / Z-429

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Henry A. Hill Art Unit : 2877
Serial No. : 10/616,504 Examiner :
Filed : July 8, 2003
Title : CYCLIC ERROR COMPENSATION IN INTERFEROMETRY SYSTEMS

Mail Stop Amendment
Commissioner for Patents
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INFORMATION DISCLOSURE STATEMENT

Please consider the references listed on the attached form PTO-1449. Copies of non-patent references are enclosed.

This statement is being filed within three months of the filing date of the application or before the receipt of a first Office Action on the merits. Please apply any charges or credits to Deposit Account No. 06-1050.

Respectfully submitted,

Date: 01/28/04



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***See attached document certifying that Marc M. Wefers has limited recognition to practice before the U.S. Patent and Trademark Office under 37 C.F.R. § 10.9(b).**

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Substitute Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 09712-330001	Application No. 10/616,504
Information Disclosure Statement by Applicant (Use several sheets if necessary) (37 CFR §1.98(b))		Applicant Henry A. Hill	
		Filing Date July 8, 2003	Group Art Unit 2877

U.S. Patent Documents							
Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA	4,413,908	11/1983	Abrams et al.			
	AB	4,948,254	08/1990	Ishida			
	AC	5,151,749	09/29/1992	Tanimoto et al.			
	AD	5,249,016	9/1993	Tanaka, Hiroshi			
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	AZ	6,271,923	08/07/2001	Hill			
	AAA	6,304,318	10/16/2001	Matsumoto			

Examiner Signature	Date Considered
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	

Substitute Form PTO-1449 (Modified)		U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 09712-330001	Application No. 10/616,504
Information Disclosure Statement by Applicant <small>(Use several sheets if necessary)</small> <small>(37 CFR §1.58(b))</small>		Applicant Henry A. Hill		
		Filing Date July 8, 2003	Group Art Unit 2877	

U.S. Patent Documents

Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	ABB	6,313,918	11/06/2001	Hill et al.			
	ACC	6,687,013	02/2004	Isshiki et al.			
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	AEE	6,806,961	10/19/2004	Hill			
	AFF	2002/0048026 A1	04/25/2002	Isshiki et al.			

Foreign Patent Documents or Published Foreign Patent Applications

Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
	AGG	JP 7-351078	12/1995	Japan (Abstract Only)				
	AHH	JP 8-117083	04/1996	Japan (Abstract Only)				
	AII	JP 10-260009	09/29/1998	Japan (with Abstract)				X
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Other Documents (include Author, Title, Date, and Place of Publication)

Examiner Initial	Desig. ID	Document
	AKK	Badami V.G. et al., "Investigation of Nonlinearity in High Accuracy Heterodyne Laser Interferometry," 1997 PROCEEDINGS, Vol. 16, pp. 153-156.
	ALL	Bennett, S.J. <u>Optics Communications</u> , 4:6, pp. 428-430, 1972
	AMM	Bobroff, N., "Recent Advances in Displacement Measuring Interferometry," MEASUREMENT SCIENCE & TECHNOLOGY, Vol. 4, No. 9, September 1993, pp. 907-926.
	ANN	Hines, B. et al., "Sub-Nanometer Laser Metrology - Some Techniques and Models," JET PROPULSION LABORATORY, CALIFORNIA INSTITUTE OF TECHNOLOGY, pp. 1195-1204.
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	APP	Wu, C.M. et al., "Analytical Modeling of the Periodic Nonlinearity in Heterodyne Interferometry," APPLIED OPTICS, Vol. 37, No. 28, 1 October 1998, pp. 6696-6700.
	AQQ	

Examiner Signature	Date Considered
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